



Subject card

Subject name and code	Physical methods of materials testing , PG_00058939						
Field of study	Nanotechnology						
Date of commencement of studies	October 2022	Academic year of realisation of subject			2023/2024		
Education level	first-cycle studies	Subject group			Obligatory subject group in the field of study Subject group related to scientific research in the field of study		
Mode of study	Full-time studies	Mode of delivery			at the university		
Year of study	2	Language of instruction			Polish		
Semester of study	4	ECTS credits			2.0		
Learning profile	general academic profile	Assessment form			assessment		
Conducting unit	Instytut Nanotechnologii i Inżynierii Materiałowej -> Faculty of Applied Physics and Mathematics						
Name and surname of lecturer (lecturers)	Subject supervisor	dr inż. Marcin Łapiński					
	Teachers	dr inż. Marcin Łapiński					
Lesson types and methods of instruction	Lesson type	Lecture	Tutorial	Laboratory	Project	Seminar	SUM
	Number of study hours	30.0	0.0	0.0	0.0	0.0	30
	E-learning hours included: 0.0						
Learning activity and number of study hours	Learning activity	Participation in didactic classes included in study plan	Participation in consultation hours	Self-study	SUM		
	Number of study hours	30	2.0	18.0	50		
Subject objectives	The aim of the course is to present the possibilities of modern measurement techniques, along with a description of appropriate measurement systems, methods of analyzing the results leading to the determination of structure parameters (macro-, micro- and nanoscopic, as well as at the atomic level) of the tested materials, determining the chemical composition and physical properties chemical and thermal.						
Learning outcomes	Course outcome	Subject outcome			Method of verification		
	K6_W10	The student is able to analyze the research problem, select a research method and plan a physical experiment to solve the problem. Is aware of the limitations related to the use of specific experimental methods.			[SW1] Assessment of factual knowledge		
	K6_W07	The student acquires extensive knowledge of methods for analyzing the physical properties of materials and nanomaterials. He learns both the theoretical foundations (in terms of the main phenomena, laws and relationships) as well as the technical and application aspects of the research methods discussed.			[SW1] Assessment of factual knowledge		
	K6_U02	The student has extended theoretical knowledge of research methods and techniques used in nanotechnology and materials engineering. Is able to select an appropriate experimental method to solve a given research problem.			[SU3] Assessment of ability to use knowledge gained from the subject [SU2] Assessment of ability to analyse information		

Subject contents	<p>1. Introduction;</p> <p>2. Diffraction methods - theoretical basis:</p> <ul style="list-style-type: none"> - X-ray diffraction; - Neutron diffraction; - Electron diffraction. <p>3. EM radiation sources;</p> <p>4. Detectors of ionizing radiation;</p> <p>5. Synchrotron, synchrotron radiation and its application.</p> <p>6. Spectroscopic methods - introduction and theoretical basis:</p> <ul style="list-style-type: none"> - Molecular spectroscopy (microwave, IR, Raman, UV-Vis); - Photoelectron spectroscopy (PES) and Auger electron spectroscopy (AES); - X-ray absorption spectroscopy (XAS). <p>7. Structure imaging methods:</p> <ul style="list-style-type: none"> - Electron microscopy (SEM, TEM, STEM); - Scanning probe microscopy (STM, AFM); - Confocal microscopy. <p>6. Thermal analysis (DTA, DSC, TGA).</p> <p>7. Methods of testing material porosity (mercury porosimetry, gas porosimetry, micro-CT)</p> <p>Prerequisites and co-requisites</p> <p>The basics knowledge of physics, crystallography, general chemistry and materials engineering</p>											
Prerequisites and co-requisites	The basics knowledge of physics and crystallography,.											
Assessment methods and criteria	<table border="1" data-bbox="448 642 1487 719"> <thead> <tr> <th data-bbox="448 642 794 680">Subject passing criteria</th> <th data-bbox="794 642 1141 680">Passing threshold</th> <th data-bbox="1141 642 1487 680">Percentage of the final grade</th> </tr> </thead> <tbody> <tr> <td data-bbox="448 680 794 719">writing exam</td> <td data-bbox="794 680 1141 719">51.0%</td> <td data-bbox="1141 680 1487 719">100.0%</td> </tr> </tbody> </table>			Subject passing criteria	Passing threshold	Percentage of the final grade	writing exam	51.0%	100.0%			
Subject passing criteria	Passing threshold	Percentage of the final grade										
writing exam	51.0%	100.0%										
Recommended reading	<table border="1" data-bbox="448 725 1487 1357"> <tbody> <tr> <td data-bbox="448 725 794 920">Basic literature</td> <td colspan="2" data-bbox="794 725 1487 920"> [1] A. Oleś, Metody doświadczalne fizyki ciała stałego, WNT (in polish) [2] J.Przedmojski, Rentgenowskie metody badawcze w Inżynierii Materiałowej, WNT (in polish) [3a] J. Sadlej, Spektroskopia molekularna, WNT, Warszawa (in polish) [3b] Z. Kęcki, Podstawy spektroskopii molekularnej, PWN, Warszawa (in polish) [4] A. Kisiel, Synchrotron jako narzędzie: zastosowanie PS w spektroskopii ciała stałego, SRNS 5(3) (2006) (in polish) </td> </tr> <tr> <td data-bbox="448 927 794 1263">Supplementary literature</td> <td colspan="2" data-bbox="794 927 1487 1263"> [5] Ch. Kittel, P. McEuen, Introduction to solid state physics (9th Ed.), New Jersey: Wiley [6a] W. Moebis, S.J. Ling, J.S. Sanny, University Physics, OpenStax, Volume 2 [6b] W. Moebis, S.J. Ling, J.S. Sanny, University Physics, OpenStax, Volume 3 [7] J.M. Hollas, Modern Spectroscopy, John Wiley & Sons, Ltd. [8] P. Willmott, An Introduction to Synchrotron Radiation: Techniques and Applications, John Wiley & Sons, Ltd. [9] A. Barbacki (red.), Mikroskopia elektronowa, Wyd. Politechniki Poznańskiej (in polish) [10] P. Atkins, J.de Paula, Chemia fizyczna, Rozdz.16 Spektroskopia 1: widma rotacyjne i oscylacyjne; Rozdz. 17 Spektroskopia 2: przejścia elektronowe, PWN (in polish) </td> </tr> <tr> <td data-bbox="448 1270 794 1357">eResources addresses</td> <td colspan="2" data-bbox="794 1270 1487 1357"> Adresy na platformie eNauczanie: Fizyczne Metody Badań Materiałów - Moodle ID: 37956 https://enauczanie.pg.edu.pl/moodle/course/view.php?id=37956 </td> </tr> </tbody> </table>			Basic literature	[1] A. Oleś, Metody doświadczalne fizyki ciała stałego, WNT (in polish) [2] J.Przedmojski, Rentgenowskie metody badawcze w Inżynierii Materiałowej, WNT (in polish) [3a] J. Sadlej, Spektroskopia molekularna, WNT, Warszawa (in polish) [3b] Z. Kęcki, Podstawy spektroskopii molekularnej, PWN, Warszawa (in polish) [4] A. Kisiel, Synchrotron jako narzędzie: zastosowanie PS w spektroskopii ciała stałego, SRNS 5(3) (2006) (in polish)		Supplementary literature	[5] Ch. Kittel, P. McEuen, Introduction to solid state physics (9th Ed.), New Jersey: Wiley [6a] W. Moebis, S.J. Ling, J.S. Sanny, University Physics, OpenStax, Volume 2 [6b] W. Moebis, S.J. Ling, J.S. Sanny, University Physics, OpenStax, Volume 3 [7] J.M. Hollas, Modern Spectroscopy, John Wiley & Sons, Ltd. [8] P. Willmott, An Introduction to Synchrotron Radiation: Techniques and Applications, John Wiley & Sons, Ltd. [9] A. Barbacki (red.), Mikroskopia elektronowa, Wyd. Politechniki Poznańskiej (in polish) [10] P. Atkins, J.de Paula, Chemia fizyczna, Rozdz.16 Spektroskopia 1: widma rotacyjne i oscylacyjne; Rozdz. 17 Spektroskopia 2: przejścia elektronowe, PWN (in polish)		eResources addresses	Adresy na platformie eNauczanie: Fizyczne Metody Badań Materiałów - Moodle ID: 37956 https://enauczanie.pg.edu.pl/moodle/course/view.php?id=37956	
Basic literature	[1] A. Oleś, Metody doświadczalne fizyki ciała stałego, WNT (in polish) [2] J.Przedmojski, Rentgenowskie metody badawcze w Inżynierii Materiałowej, WNT (in polish) [3a] J. Sadlej, Spektroskopia molekularna, WNT, Warszawa (in polish) [3b] Z. Kęcki, Podstawy spektroskopii molekularnej, PWN, Warszawa (in polish) [4] A. Kisiel, Synchrotron jako narzędzie: zastosowanie PS w spektroskopii ciała stałego, SRNS 5(3) (2006) (in polish)											
Supplementary literature	[5] Ch. Kittel, P. McEuen, Introduction to solid state physics (9th Ed.), New Jersey: Wiley [6a] W. Moebis, S.J. Ling, J.S. Sanny, University Physics, OpenStax, Volume 2 [6b] W. Moebis, S.J. Ling, J.S. Sanny, University Physics, OpenStax, Volume 3 [7] J.M. Hollas, Modern Spectroscopy, John Wiley & Sons, Ltd. [8] P. Willmott, An Introduction to Synchrotron Radiation: Techniques and Applications, John Wiley & Sons, Ltd. [9] A. Barbacki (red.), Mikroskopia elektronowa, Wyd. Politechniki Poznańskiej (in polish) [10] P. Atkins, J.de Paula, Chemia fizyczna, Rozdz.16 Spektroskopia 1: widma rotacyjne i oscylacyjne; Rozdz. 17 Spektroskopia 2: przejścia elektronowe, PWN (in polish)											
eResources addresses	Adresy na platformie eNauczanie: Fizyczne Metody Badań Materiałów - Moodle ID: 37956 https://enauczanie.pg.edu.pl/moodle/course/view.php?id=37956											
Example issues/ example questions/ tasks being completed	<ol style="list-style-type: none"> 1. List and briefly characterize detectors of ionizing radiation. 2. Silicon crystallizes in a simple cubic system. A neutron diffraction experiment with a 10-meter detector and angle = 45° reveals that the neutrons reflected from the family of planes (111) have a time of flight of 11200 microseconds. Find the lattice constant of a silicon unit cell? 3. What is a synchrotron and how does it work? Describe the basic properties of synchrotron radiation. 4. What is a spectrum? Give and discuss the parameters that characterize the spectral line. 5. Explain the terms transmittance, absorbance and absorption coefficient. Give the relationship between them. 6. Present the idea of the Raman phenomenon and discuss the shape of the Raman spectrum. 7. Explain why the XPS technique is a "surface sensitive" technique. 8. Electron microscopy - list the types of electron microscopes, compare them and define the scope of applications. 9. Determine what thermal analysis is and what the types are. 10. Discuss the differences between physical and chemical adsorption. 											
Work placement	Not applicable											